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5/28/02

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/825,664
Filing Date April 3, 2001
Inventor David R. Hembree
Assignee Micron Technology, Inc.
Group Art Unit 2858
Examiner V. Nguyen
Attorney's Docket No. MI22-1680
Title: Electronic Device Wafer Processing Members and Wafer Processing Apparatuses

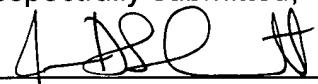
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether all the submitted references are prior art.

Dated: 5/10/02

Attorney:

Respectfully submitted,

James D. Shaurette
Reg. No. 39,833

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MI22-1680SERIAL NO.
09/825,664LIST OF ART CITED BY APPLICANT
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U.S. PATENT DOCUMENTSAPPLICANT
Micron Technology, Inc.FILING DATE
April 3, 2001GROUP
2858

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,886,863	3/23/1999	Nagasaki et al.			
	AB						
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
	AF						
	AG						
	AH						
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT David R. Hembree			
				FILING DATE April 3, 2001	GROUP 2858		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	3,440,407	4/22/69	Golstos et al.			
	AB	3,614,345	10/19/71	Quinn			
	AC	3,683,306	8/8/72	Bulthuis et al.			
	AD	4,332,081	6/1/82	Francis			
	AE	4,518,944	5/21/83	Faris			
	AF	4,703,555	11/3/87	Hubner			
	AG	5,141,334	8/25/92	Castles			
	AH	5,347,869	9/20/94	Shie et al.			
	AI	5,406,109	4/11/95	Whitney			
	AJ	5,436,646	7/25/95	McArthur et al.			
	AK	5,446,437	8/29/95	Bantien et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AL	2336778	7/1977	France			Yes
	AM	56-12521	2/1981	Kobayashi, Japan			No
	AN	2-268462	11/1990	Yamanishi, Japan			
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR	/	Application Guide Temperature Sensors. Weller Electrical Manufacturing Company Catalog, pp. 773-778, 1992/1993.				
	AS	/	In-Situ Survey System of Resistive and Thermoelectric Properties of Either Pure or Mixed Materials in Thin Films Evaporated Under Ultra High Vacuum. Lebevallier, Lethuera, Richou, Serre, & Gouault, J. Phys. III France, Vol. 5, pp. 409-418, 04/95 (Abstract only).				
	AT	/	Temperature Metrology for CD Control in DUV Lithography. Jeffrey Parker and Wayne Renken, pp. 111-112, 114, 116, 09/17/97.				
EXAMINER				DATE CONSIDERED			RECEIVED MAY 17 2002 TECHNOLOGY CENTER 2800
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		MAY 10 2002 PATENT & TRADEMARK OFFICE JC82		APPLICANT David Hendree			
				FILING DATE April 3, 2001	GROUP 2858		
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,612,574	3/18/97	Summerfelt et al.			
	AB	5,719,333	2/17/98	Hosoi et al.			
	AC	5,831,333	11/3/98	Malladi et al.			
	AD	5,919,548	7/6/99	Barron et al.			
	AE	5,551,283	9/3/96	Manaka et al.			
	AF	5,492,011	2/20/96	Amano et al.			
	AG						
	AH						
	AJ						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AK						Yes
	AL						No
	AM						
	AN						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AP		"NTC and PTC Thermistors"; http://www.thermodisc.com/ntcptc.html ; 1/7/98; 2 pages.				
	AR		"DI-5B35 Linearized 4-Wire RTD Input"; http://www.dataq.com/di5b35.html ; 1/7/98; 2 pages.				
	AS		"RTD"; http://www.mtsensors.com/rtds.html ; 1/7/98; 3 pages.				
	AT		"Low Cost Thermal-Ribbon (TM) uses thin film RTD"; http://www.minco.com/s17624nr.html ; 1/7/98; 1 page.				
	AU		"Silicon Processing for the VLSI Era"; Volume 1 - Process Technology, Second Edition; S. Wolf et al.; 2000; pp. 22-25 and pp. 841-845.				
EXAMINER							
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